Search Notes				

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/621,885	CHANG ET AL.	
Examiner	Art Unit	
John Chavis	2193	

CEARCUED			
SEARCHED			
Class	Subclass	Date	Examiner
717	174	6/21/2006	JC
717	120	6/21/2006	JC
		-	

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
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SEARCH NOT (INCLUDING SEARCH		)
	DATE	EXMR
West (IBM TDB, Derwent, EPO, JPO, PGPUBS, USPAT) anded with word search	6/21/2006	JC
Inventor search for double patenting	6/21/2006	C
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